

Notice of References Cited	Application/Control No. 10/682,542		Applicant(s)/Patent Under Reexamination WEE ET AL.	
	Examiner X. L. Bautista		Art Unit 2179	Page 1 of 1

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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